Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/813,782	MITA, KIYOSHI	
Examiner	Art Unit	
Chris C Chu	2815	

	SEARCHED					
	SEAR	CHED	i			
Class	Subclass	Date	Examiner			
257	678 & 787	11/25/2005	C.C.			
174	52.2	11/25/2005	C.C.			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	11/25/2005	C.C.
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